

Maury Microwave, AMCAD Engineering, HiTech and MRC Gigacomp invite you to our free

Device Characterization Seminar

On October 5, 2021, at H4 Hotel München Messe, Konrad-Zuse-Platz 14, 81829 München

The evolution of semiconductors is going faster than ever. The complexity of devices, circuits and complete wireless communication systems has become immense. Maury Microwave and AMCAD have introduced lately solutions to characterize these devices, simulate circuitry and systems.

Agenda:

09:30 Welcome

09:45 Characterizing Uncertainty in S-Parameter Measurements with Insight Software

10:15 Characterization Solutions for 5G FR1 and FR2 Devices

Introduction of Maury Microwave's NEW Nano5G tuners
Wide band Active Load Pull Measurements at 5G FR1 Frequencies using MT2000

11:15 Break & Demo

11:30 Overcoming Tuning Range Limitations with Maury's mmWave Hybrid Active VRLP Solutions

Characterizing high power devices for frequencies between 50GHz and 110GHz where $|\Gamma|=1$

12:30 Lunch & Demo

13:30 mmW and Sub-THz 50Ω Gain Compression and Active Load Pull Measurements

Measure power controlled S-parameters accurately and characterize devices above 110 GHz with mmWave Studio Active Load Pull.

14:15 Revealing Hidden Instabilities in Multistage Power Amplifiers under Large Signal Conditions

Analyze instabilities and oscillations with simulation software and real measurements through pole-zero identification with the help of AMCAD STAN Software.

15:00 Break & Demo

15:15 Anticipating RF Power Amplifier Performance with AMCAD's IQSTAR Measurement Solution

Power amplifiers are inherently nonlinear. IQSTAR 1.2 introduces several DPD techniques and algorithms to verify that the power amplifier under test can be linearized with more or less complexity

16:00 Simulating Realistic Communication System Performance using AMCAD VISION

Taking different memory effects into account results in realistic results when simulating complex communication systems.

17:00 End

The seminar is free of charge, lunch and drinks are included. Please let us know if you are interested and we hope to welcome you at this event.

Your device characterization team:

Sandra Fermián Rodríguez, Oliver Kanzler, Jim Creed, Chris Caenen, Dirk Faber and Dr. Bernd Fleischmann

